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SERIAL NUMBER 10/728,917	FILING DATE 12/08/2003  RULE	CLASS 365	GROUP ART UNIT 2824	ATTORNEY DOCKET NO. 246236US2S
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## APPLICANTS

Yuui Shimizu, Yokohama-shi, JAPAN;  
 Yoshihisa Iwata, Yokohama-shi, JAPAN;  
 Kenji Tsuchida, Kawasaki-shi, JAPAN; Tatsuya Kishi, Yokohama-shi, JAPAN;

## \*\* CONTINUING DATA \*\*\*\*\*

NONE

## \*\* FOREIGN APPLICATIONS \*\*\*\*\*

JAPAN 2003-300493 08/25/2003

## IF REQUIRED, FOREIGN FILING LICENSE GRANTED

\*\* 03/05/2004

Foreign Priority claimed	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	STATE OR COUNTRY	SHEETS	TOTAL CLAIMS	INDEPENDENT CLAIMS
35 USC 119 (a-d) conditions met	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	Met after Allowance			
Verified and Acknowledged Examiner's Signature		Initials	DRAWING 13	13	2

## ADDRESS

22850  
 OBLON, SPIVAK, MCCLELLAND, MAIER & NEUSTADT, P.C.  
 1940 DUKE STREET  
 ALEXANDRIA, VA  
 22314

## TITLE

Magnetic random access memory having test circuit and test method therefor

FILING FEE RECEIVED 900	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:	<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees ( Filing ) <input type="checkbox"/> 1.17 Fees ( Processing Ext. of time ) <input type="checkbox"/> 1.18 Fees ( Issue ) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit
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10/728917

Classification: 365/158.000

Status: 30 - DOCKETED NEW CASE - READY FOR EXAMINATION

Title: MAGNETIC RANDOM ACCESS MEMORY HAVING TEST CIRCUIT AND TEST METHOD THEREFOR

Examiner: HUR, JOHN

Inventor: SHIMIZU , YUUI, et al

GAU: 2824

Bib Data report

**Application Title: MAGNETIC RANDOM ACCESS MEMORY  
HAVING TEST CIRCUIT AND TEST METHOD THEREFOR**

**Application Num:  (in phx) 10728917 Filing Date:  
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**State or Country: JAPAN Sheets/Drawing: 13 Total  
Claims: 13 Independent Claims: 2**

▼ Inventors:

Last name, First  
name:

**SHIMIZU, YUUI**

City:

**YOKOHAMA-SHI**

Country or  
State:

**JAPAN**

**MAITA**

**YOKOHAMA-SHI**

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IWABA

TOKOROZAWA-SHI

JAPAN

YOSHIHISA

TSUCHIDA

KENJI

KAWASAKI-SHI

JAPAN

KISHI, TATSUYA

YOKOHAMA-SHI

JAPAN

Attorneys: ALL Attorney Docket No: 246236US2S

Interference No: Lost Case: No Unmatched Petition:  
No L&R Code: 1